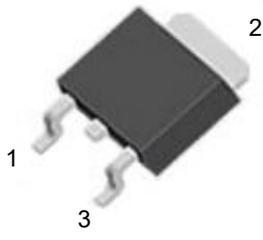
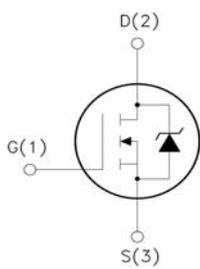


<p><b>XXW5N50</b></p> <p><b>Features:</b></p> <ul style="list-style-type: none"> <li><input type="checkbox"/> Low Intrinsic Capacitances.</li> <li><input type="checkbox"/> Excellent Switching Characteristics.</li> <li><input type="checkbox"/> Extended Safe Operating Area.</li> <li><input type="checkbox"/> Unrivalled Gate Charge :Qg=13nC (Typ.).</li> <li><input type="checkbox"/> V<sub>DSS</sub>=500V, I<sub>D</sub>=5A</li> <li><input type="checkbox"/> R<sub>DS(on)</sub> : 1.4Ω (Max) @V<sub>G</sub>=10V</li> <li><input type="checkbox"/> 100% Avalanche Tested</li> </ul>	<p style="text-align: center;">TO-252</p>    <p style="text-align: right;">1.Gate (G) 2.Drain (D) 3.Source (S)</p>
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### Absolute Maximum Ratings (Ta=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V <sub>DSS</sub>	Drain-Source Voltage	500	V
I <sub>D</sub>	Drain Current	T <sub>j</sub> =25°C	5.0
		T <sub>j</sub> =100°C	2.2
V <sub>GSS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (note1)	270	mJ
I <sub>AR</sub>	Avalanche Current (note2)	5.0	A
P <sub>D</sub>	Power Dissipation (T <sub>j</sub> =25°C)	25	W
T <sub>j</sub>	Junction Temperature(Max)	150	°C
T <sub>stg</sub>	Storage Temperature	-55~+150	°C
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	°C

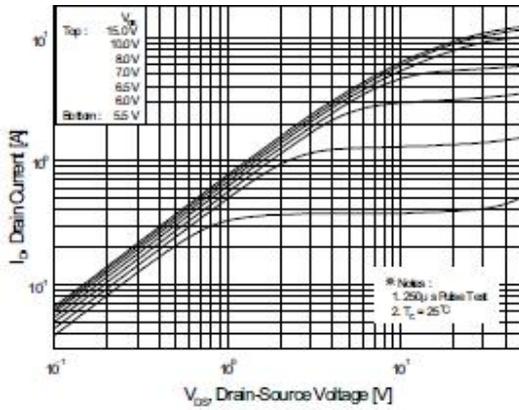
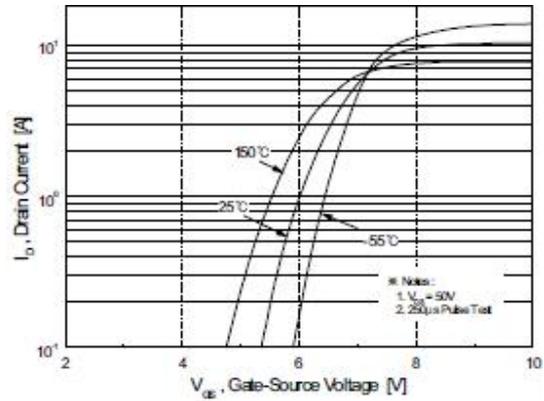
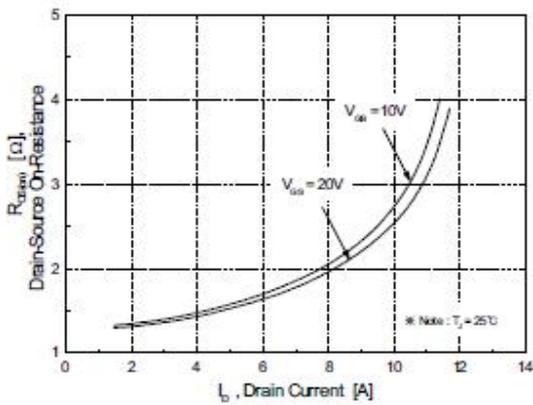
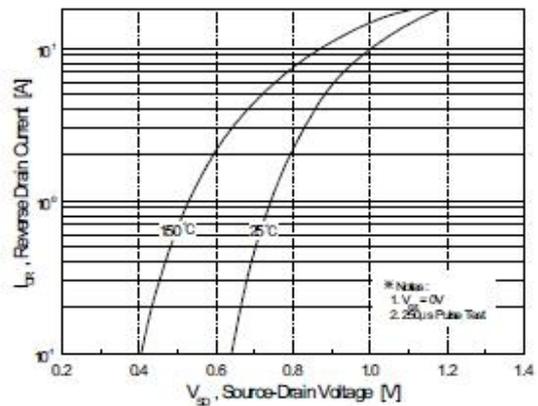
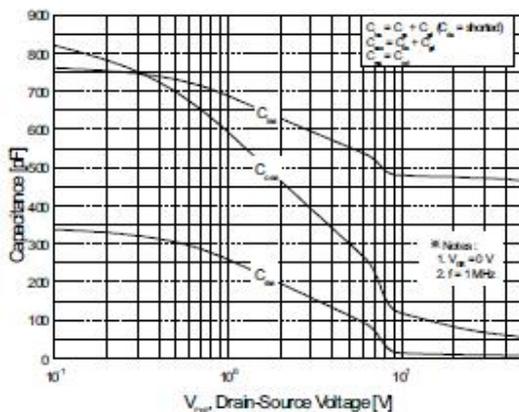
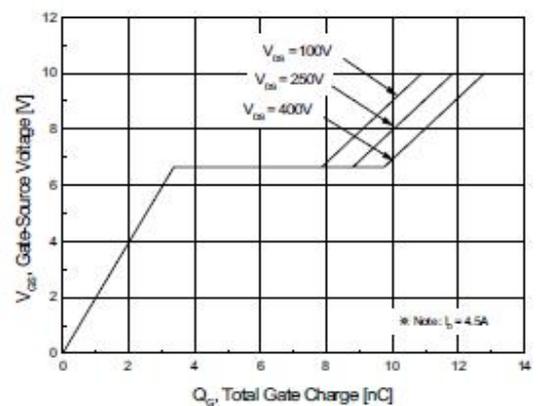
### Thermal Characteristics

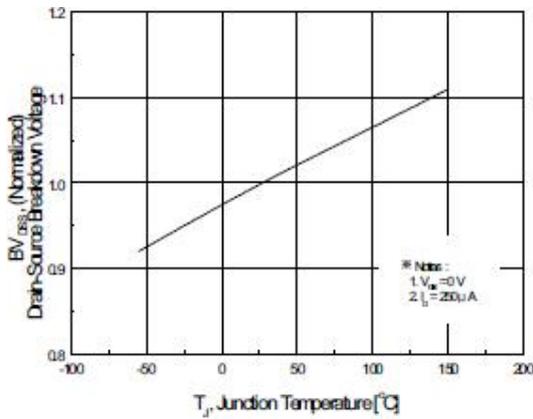
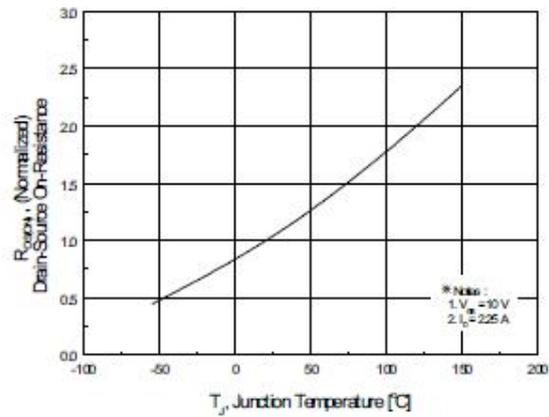
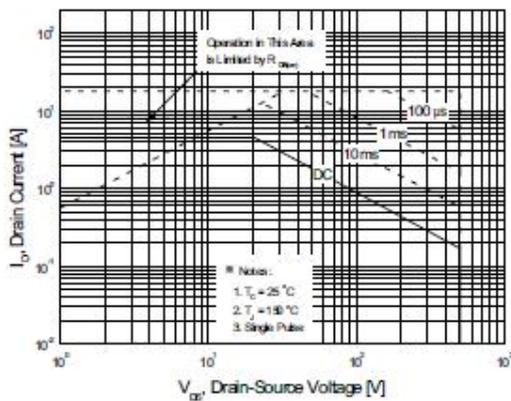
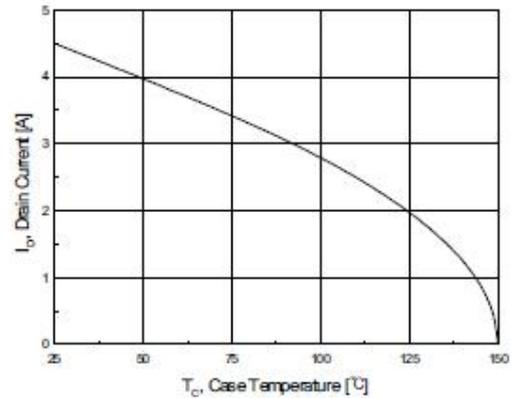
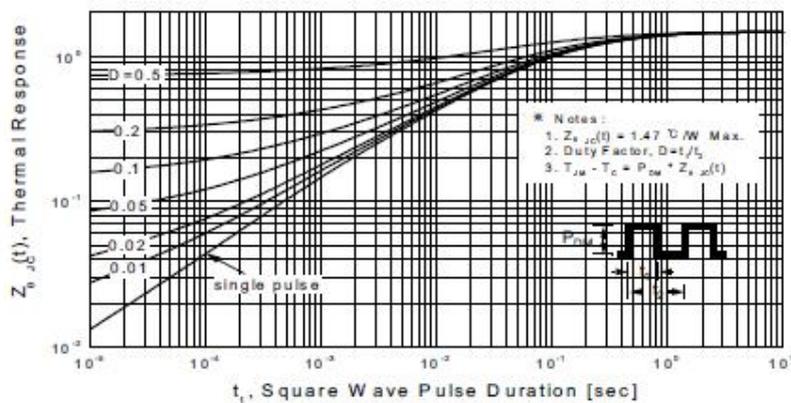
Symbol	Parameter	Typ.	Max.	Unit
R <sub>θJC</sub>	Thermal Resistance, Junction to Case	-	3.45	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient	-	110	°C/W

**Electrical Characteristics** (Ta=25°C unless otherwise noted)

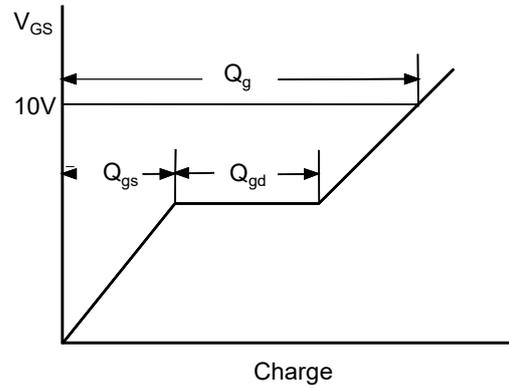
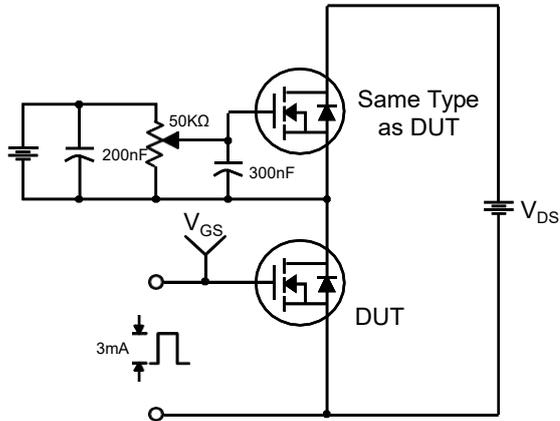
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0	500	-	-	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> =250μA, Reference to 25°C	-	0.47	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =500V, V <sub>GS</sub> =0V	-	-	1	μA
		V <sub>DS</sub> =400V, T <sub>J</sub> =125°C			10	
I <sub>GSSF</sub>	Gate-body leakage Current, Forward	V <sub>GS</sub> =+30V, V <sub>DS</sub> =0V	-	-	100	nA
I <sub>GSSR</sub>	Gate-body leakage Current, Reverse	V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V	-	-	-100	
<b>On Characteristics</b>						
V <sub>GS(TH)</sub>	Date Threshold Voltage	I <sub>D</sub> =250μA, V <sub>DS</sub> =V <sub>GS</sub>	2	-	4	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	I <sub>D</sub> =2.5A, V <sub>GS</sub> =10V	-	-	1.4	Ω
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0, f=1.0MHz	-	620	-	pF
C <sub>oss</sub>	Output Capacitance		-	70	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	8	-	
<b>Switching Characteristics</b>						
T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> =250V, I <sub>D</sub> =5A R <sub>G</sub> =25Ω (Note 3,4)	-	13	35	ns
T <sub>r</sub>	Turn-On Rise Time		-	55	120	
T <sub>d(off)</sub>	Turn-Off Delay Time		-	25	60	
T <sub>f</sub>	Turn-Off Rise Time		-	35	80	
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =400V, V <sub>GS</sub> =10V, I <sub>D</sub> =5A (Note 3,4)	-	13	17	nC
Q <sub>gs</sub>	Gate-Source Charge		-	3.4	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	6.4	-	
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Max. Diode Forward Current	-	-	-	5.0	A
I <sub>SM</sub>	Max. Pulsed Forward Current	-	-	-	20	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>D</sub> =5A	-	-	1.5	V
T <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =5A, V <sub>GS</sub> =0V diF/dt=100A/μs (Note3)	-	215	-	nS
Q <sub>rr</sub>	Reverse Recovery Charge		-	1.26	-	μC

- Notes : 1, L=27mH, I<sub>AS</sub>=5A, V<sub>DD</sub>=50V, R<sub>G</sub>=25Ω, Starting T<sub>J</sub>=25°C  
 2, Repetitive Rating : Pulse width limited by maximum junction temperature  
 3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%  
 4, Essentially Independent of Operating Temperature

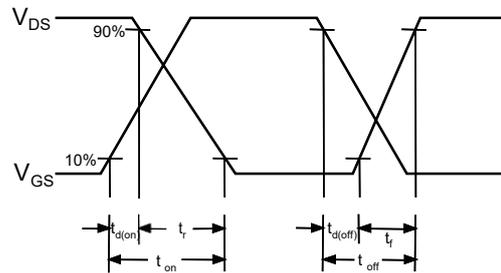
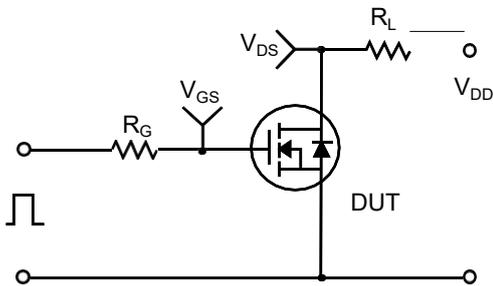
**Typical Characteristics**

**Figure 1. On-Region Characteristics**

**Figure 2. Transfer Characteristics**

**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**

**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

**Figure 5. Capacitance Characteristics**

**Figure 6. Gate Charge Characteristics**

**Typical Characteristics (Continued)**

**Figure 7. Breakdown Voltage Variation vs. Temperature**

**Figure 8. On-Resistance Variation vs. Temperature**

**Figure 9. Maximum Safe Operating Area**

**Figure 10. Maximum Drain Current vs. Case Temperature**

**Figure 11. Transient Thermal Response Curve**

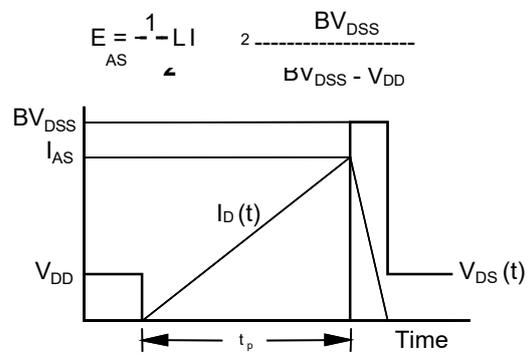
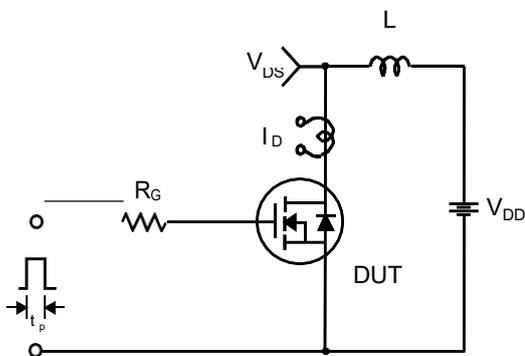
**Gate Charge Test Circuit & Waveform**



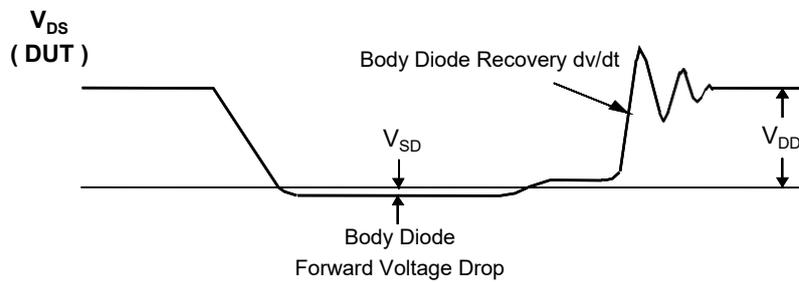
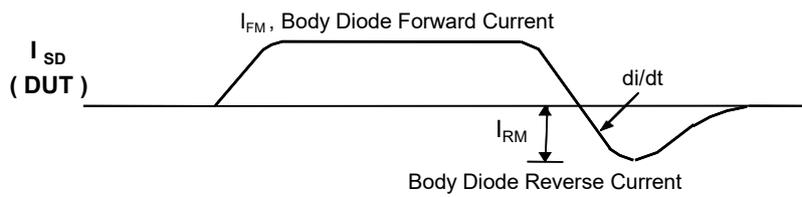
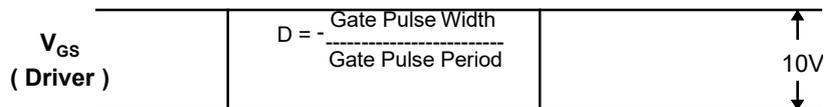
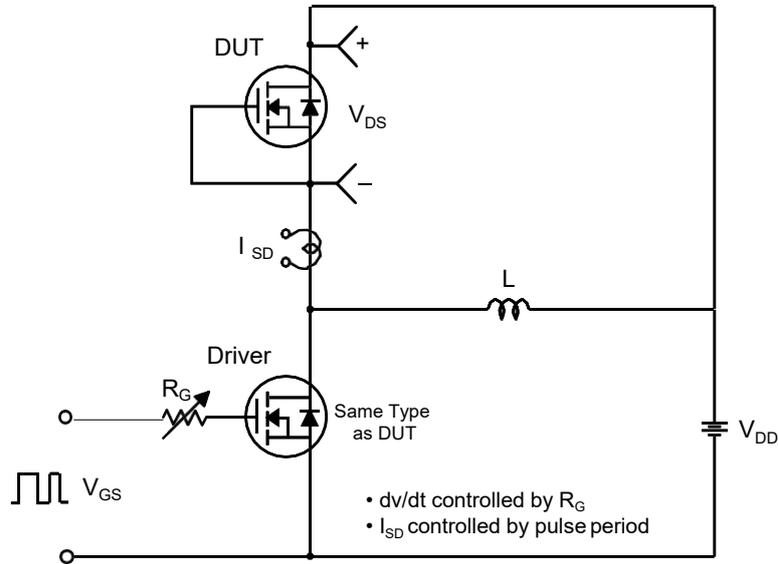
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**



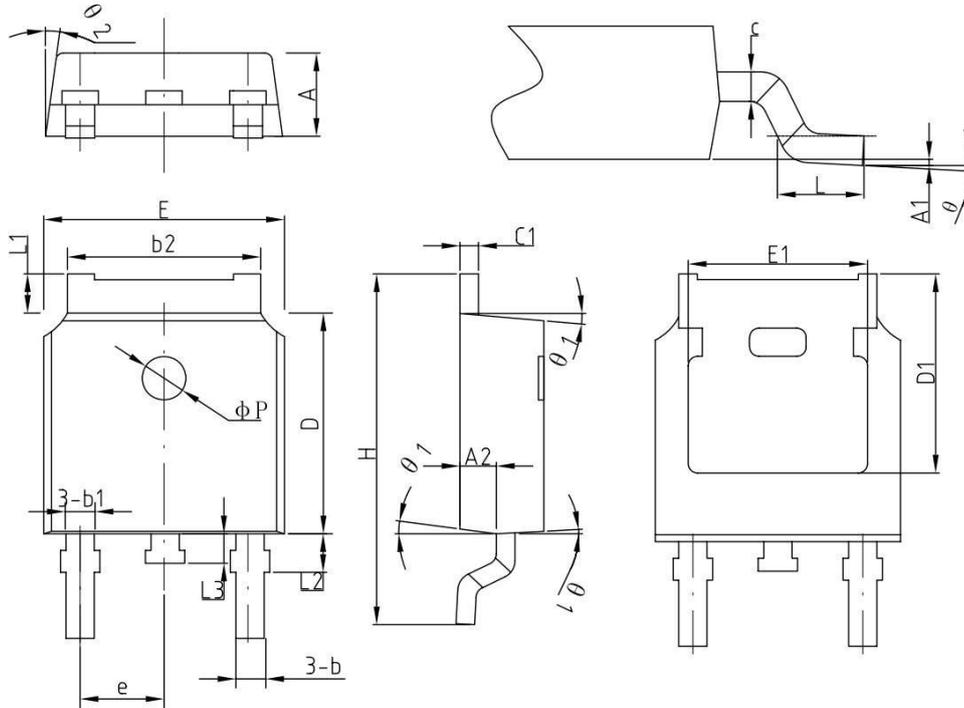
**Peak Diode Recovery dv/dt Test Circuit & Waveforms**



## Package Dimension

### TO-252

Unit: mm



COMMON DIMENSIONS  
 (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	2.2	2.30	2.38
A1	0	—	0.10
A2	0.90	1.01	1.10
b	0.71	0.76	0.86
b1		0.76	
b2	5.13	5.33	5.46
c	0.47	0.50	0.60
c1	0.47	0.50	0.60
D	6.0	6.10	6.20
D1	—	5.30	—
E	6.50	6.60	6.70
E1	—	4.80	—
e	2.286BSC		
H	9.70	10.10	10.40
L	1.40	1.50	1.70
L1	0.90	—	1.25
L2		1.05	
L3		0.8	
$\phi P$		1.2	
$\theta$	0°	—	8°
$\theta 1$	5°	7°	9°
$\theta 2$	5°	7°	9°